

STD50NH02L STD50NH02L-1

N-channel 24V - 0.0085Ω - 50A - DPAK/IPAK STripFET™ III Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STD50NH02L-1	24V	<0.0105Ω	50A
STD50NH02L	24V	<0.0105Ω	50A

- Logic level device
- R_{DS(ON)} * Q_g Industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold drive

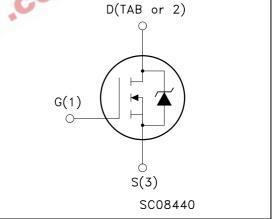
Description

This device utilizes the latest advanced design rules of ST's proprietary STripFET™ technology. This is suitable fot the most demanding DC-DC converter application where high efficiency is to be achieved.

Applications

Switching application





Order codes

Part number	Marking	Package	Packaging
STD50NH02L-1	D50NH02L	IPAK	Tube
STD50NH02LT4	D50NH02L	DPAK	Tape & reel

Contents

1	Electrical ratings
2	Electrical characteristics
	2.1 Electrical characteristics (curves)
3	Test circuit
4	Appendix A
5	Package mechanical data
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Electrical ratings

Table 1.	Absolute	maximum	ratings
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Symbol	Parameter	Value	Unit
V _{spike} ⁽¹⁾	Drain-source voltage rating	30	V
V_{DS}	Drain-source voltage (V _{GS} = 0)	24	V
V _{DGR}	Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)	24	V
V _{GS}	Gate- source voltage	± 20	V
۱ _D	Drain current (continuous) at $T_C = 25^{\circ}C$	50	А
۱ _D	Drain current (continuous) at $T_C = 100^{\circ}C$	36	А
I _{DM} ⁽²⁾	Drain current (pulsed)	200	А
P _{tot}	Total dissipation at $T_{C} = 25^{\circ}C$	60	W
	Derating Factor	0.4	W/°C
E _{AS} ⁽³⁾	Single pulse avalanche energy	280	mJ
T _{stg}	Storage temperature	3 M	°C
Тj	Max. operating junction temperature	-55 to 175	-0
Pulse width	hen external R_g =4.7 Ω and $t_f < t_{fmax}$. limited by safe operating area. 25 °C, I_D = 19A, V_{DD} = 18V	n.C.	

Table 2.	Thermal of	data
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Rthj-case	Thermal resistance junction-case max	2.5	°C/W
Rthj-amb	Thermal resistance junction-ambient max	100	°C/W
TJ	Maximum lead temperature for soldering purpose	275	°C

Electrical characteristics 2

(T_{CASE}=25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 25mA, V _{GS} =0	24			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	$V_{DS} = 20V$ $V_{DS} = 20V$, $T_{C} = 125^{\circ}C$			1 10	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	$V_{GS} = \pm 20V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1	1.8		V
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10V, I_D = 25A$ $V_{GS} = 5V, I_D = 12.5A$		0.0085 0.012	0.0105 0.020	Ω Ω

Table 3. **On/off states**

Table	4.	Dynamic

Table 4.	Dynamic	a to the				
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs} ⁽¹⁾	Forward transconductance	V _{DS} = 15V, I _D = 25A		27		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25V$, f = 1MHz, $V_{GS} = 0$		1400 400 55		pF pF pF
R _G	Gate Input Resistance	f = 1 MHz Gate DC Bias = 0 Test Signal Level = 20 mV Open Drain		1		Ω
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 10V, I_D = 25A$ $R_G = 4.7\Omega V_{GS} = 10V$ (see <i>Figure 13</i>)		10 130 27 16		ns ns ns ns
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 10V, I_D = 50A,$ $V_{GS} = 10V, R_G = 4.7\Omega$ (see <i>Figure 14</i>)		24 5 3.5		nC nC nC
Q _{oss} ⁽²⁾	Output charge	V_{DS} = 16 V, V_{GS} = 0 V		9.5		nC

1. Pulsed: Pulse duration = $300 \ \mu s$, duty cycle 1.5 %.

2. Qoss = Coss^{*} Δ Vin , Coss = Cgd + Cds . See *Chapter 4: Appendix A*



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)				50 200	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 25A, V _{GS} = 0			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 50A, di/dt = 100A/\mu s,$ $V_{DD} = 20V, T_j = 150^{\circ}C$ (see <i>Figure 15</i>)		36 36 2		ns nC A

Table 5. Source drain diode

1. Pulse width limited by safe operating area.

2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %



 $Z_{th} = k R_{thJ-c}$

10^{-1 †}p(s)

 $\delta = t_p / \tau$

10-2

Electrical characteristics (curves) 2.1

Figure 1. Safe operating area



280DPC

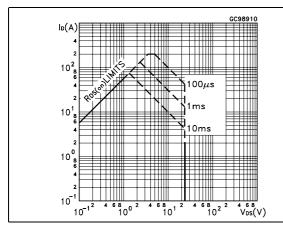
d = 0.5

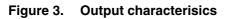
к

10

10

10⁻⁵







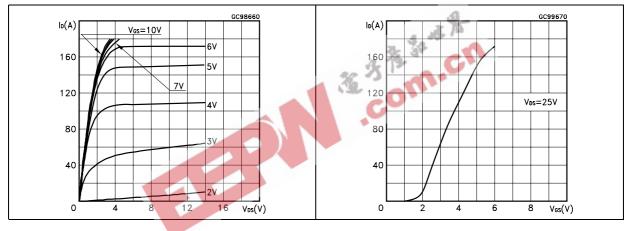
SINGLE PULSE

0.05

0.02

0.01

<u>10⁻³</u>





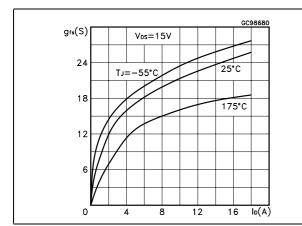


Figure 6. Static drain-source on resistance

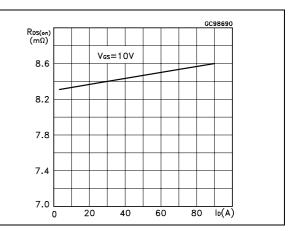


Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

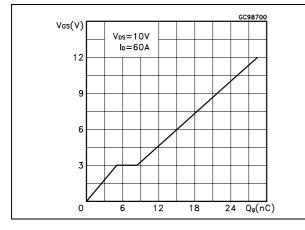


Figure 9. Normalized gate threshold voltage vs temperature

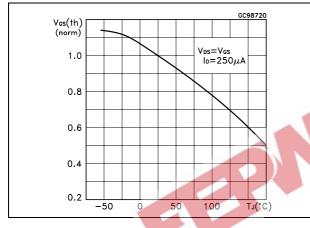


Figure 11. Source-drain diode forward characteristics

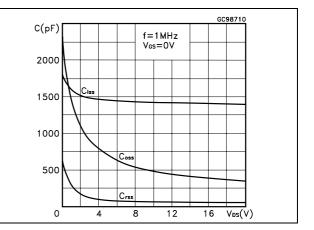


Figure 10. Normalized on resistance vs temperature

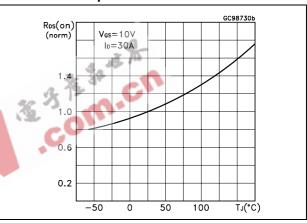
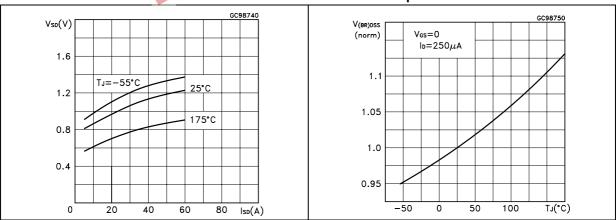


Figure 12. Normalized breakdown voltage vs temperature



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3 Test circuit

Figure 13. Switching times test circuit for resistive load

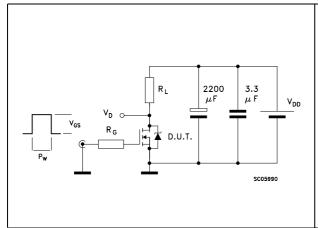
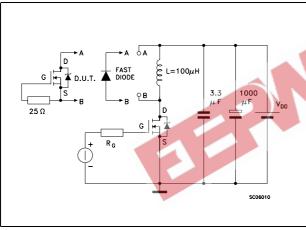


Figure 15. Test circuit for inductive load switching and diode recovery times





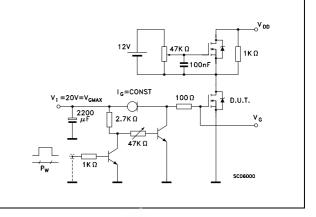
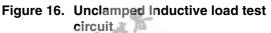


Figure 14. Gate charge test circuit



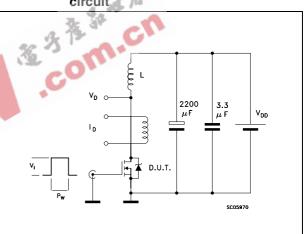
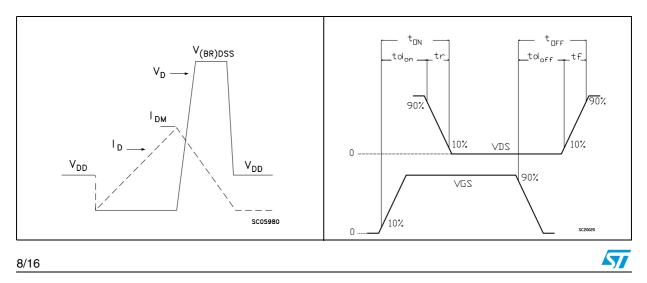
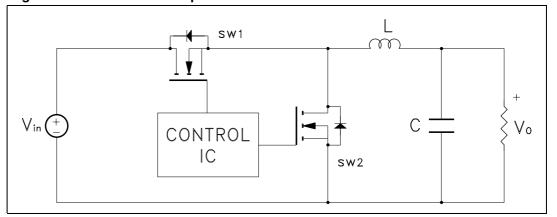


Figure 18. Switching time waveform



4 Appendix A





The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

- The low side (SW2) device requires:
- Very low R_{DS(on)} to reduce conduction losses
- Small QgIs to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Qrr to reduce losses on SW1 during its turn-on
- The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source
- voltage to avoid the cross conduction phenomenon;
- The high side (SW1) device requires:
- Small Rg and Ls to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Qg to have a faster commutation and to reduce gate charge losses
- Low R_{DS(on)} to reduce the conduction losses.



	High side switching (SW1)	Low side switch (SW2)
luction	$R_{DS(on)SW1} * I_L^2 * \delta$	$R_{DS(on)SW2} * I_L^2 * (1 - \delta)$
ching	$V_{in} * (Q_{gsth(SW1)} + Q_{gd(SW1)}) * f * \frac{I_L}{I_g}$	Zero Voltage Switching
Recovery	Not applicable	$V_{in} * Q_{rr(SW2)} * f$
Conductio n	Not applicable	$V_{f(SW2)} * I_L * t_{deadtime} * f$
e(Q _G)	$Q_{g(SW1)} * V_{gg} * f$	$Q_{gls(SW2)} * V_{gg} * f$
loss	$\frac{V_{in} * Q_{oss(SW1)} * f}{2}$	$\frac{V_{in} * Q_{oss(SW2)} * f}{2}$
	ching Recovery (1) Conductio n	R $R_{DS(on)SW1} * I_L^* * \delta$ ching $V_{in} * (Q_{gsth(SW1)} + Q_{gd(SW1)}) * f * \frac{I_L}{I_g}$ Recovery Not applicable Conductio Not applicable Q_{QG} $Q_{g(SW1)} * V_{gg} * f$

Table 6. Power losses calculation

Paramiters meaning Table 7.

Parameter	Meaning		
d	Duty-cycle		
Q _{gsth}	Q _{gsth} Post threshold gate charge		
Q _{gls} Third quadrant gate charge			
Pconduction	On state losses		
Pswitching	On-off transition losses		
Pdiode	Conduction and reverse recovery diode losses		
Pgate	Gate drive losses		
P _{Qoss}	Output capacitance losses		



5 Package mechanical data

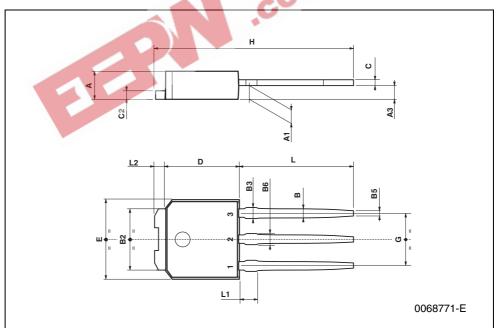
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



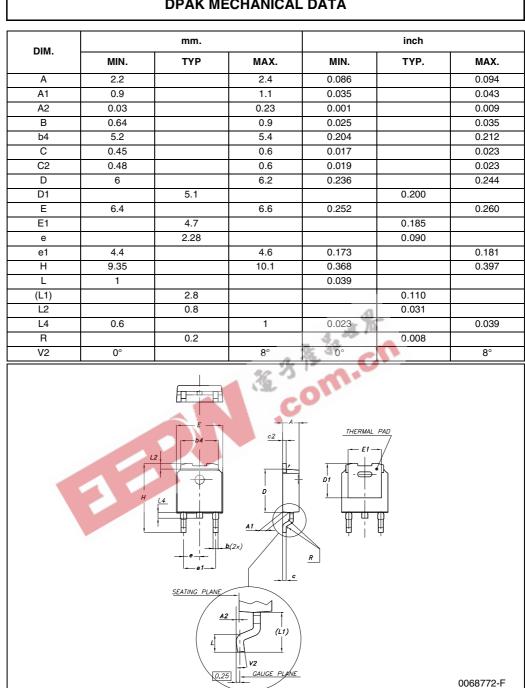


DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
B3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
E	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626	-	0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	13. T		0.031	0.039

TO-251 (IPAK) MECHANICAL DATA







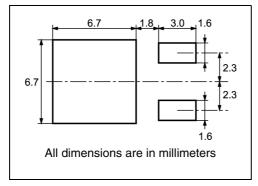
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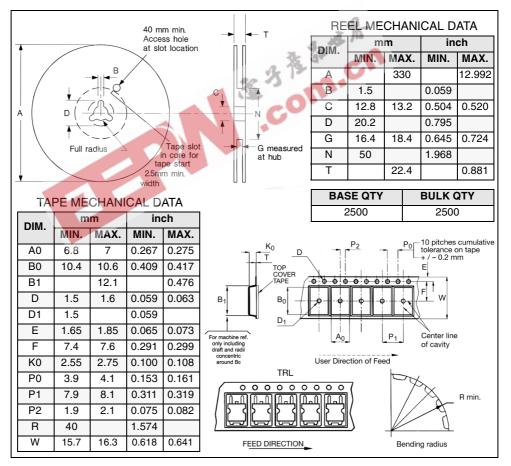


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6 Packing mechanical data

DPAK FOOTPRINT





TAPE AND REEL SHIPMENT

7 Revision history

Table 8.	Revision	history
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Date	Revision	Changes
21-Jun-2004	6	Preliminary version
11-Jul-2006	7	New template, no content change





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